

PSMN013-30KL

N-channel 30 V 13 m Ω logic-level MOSFET in SO8 Rev. 01 — 14 April 2011 Object

Objective data sheet

1. **Product profile**

1.1 General description

Logic level N-channel enhancement mode MOSFET in SO8 package qualified to 150 °C. This product is designed and qualified for use in a wide range of industrial, communications and power supply equipment

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- High performance replacement for legacy SO8 designs
- Suitable for logic-level gate drive
- Suitable for wave and reflow soldering

1.3 Applications

- DC-to-DC converters
- Load switching

Portable equipment

1.4 Quick reference data

Quick reference data Table 1.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	30	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u>	-	-	12	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	3	W
T _j	junction temperature		-55	-	150	°C
Static char	acteristics					
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 5 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 12</u>	-	16.2	19	mΩ
resistance		$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 12</u>	-	11.1	13	mΩ



Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Dynamic ch	naracteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; V_{DS} = 15 \text{ V};$		1.9	-	nC
Q _{G(tot)}	total gate charge	see Figure 14; see Figure 15	-	11.7	-	nC
		$V_{GS} = 4.5 \text{ V}$; $I_D = 5 \text{ A}$; $V_{DS} = 15 \text{ V}$; see Figure 14; see Figure 15	-	5.7	-	nC
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C;}$ $I_D = 12 \text{ A; } V_{sup} \le 30 \text{ V; } R_{GS} = 50 \Omega;$ unclamped	-	-	43	mJ

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	8 <u>7 7 7 7</u> 5	D
3	S	source		G (FA)
4	G	gate		
5	D	drain	1 1 1 1 1 4	mbb076 S
6	D	drain	SOT96-1 (SO8)	
7	D	drain		
8	D	drain		

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
PSMN013-30KL	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	$T_i \ge 25 \text{ °C}; T_i \le 150 \text{ °C}$	-	30	V
V _{DGR}	drain-gate voltage	$T_i \ge 25 \text{ °C}; T_i \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
V _{GS}	gate-source voltage	,,	-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see Figure 1	-	12	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	8	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 \text{ °C}$; see Figure 3	-	46	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	3	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
T _{sld(M)}	peak soldering temperature		-	260	°C
Source-drain	n diode				
Is	source current	T _{mb} = 25 °C	-	12	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	46	Α
Avalanche ru	uggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 12 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω ; unclamped	-	43	mJ

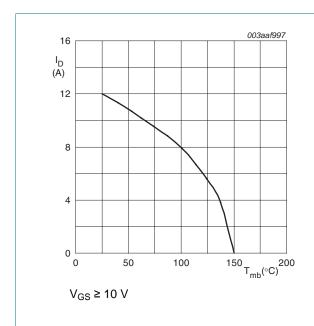


Fig 1. Continuous drain current as a function of mounting base temperature

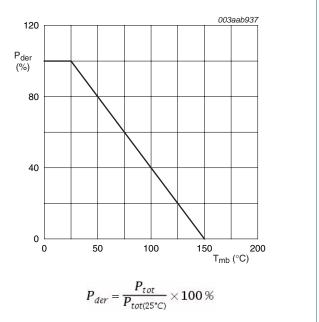
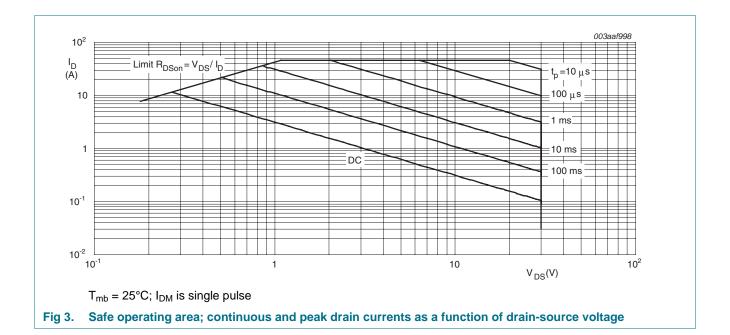


Fig 2. Normalized total power dissipation as a function of solder point temperature



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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	see Figure 4	-	30	40	K/W

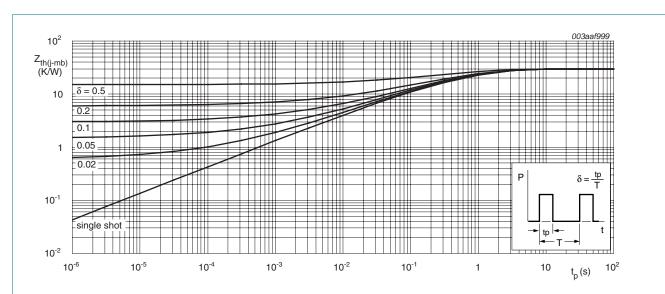


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration; typical values

6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	cteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	30	-	-	V
	voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	1.3	1.7	2.15	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 11</u>	-	-	2.55	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see <u>Figure 11</u>	0.5	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.1	1	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125 \text{ °C}$	-	-	50	μA
I_{GSS}	gate leakage current	$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
DOON	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 12</u>	-	16.2	19	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; T_j = 100 ^{\circ}\text{C};$ see <u>Figure 13</u> ; see <u>Figure 12</u>	-	-	17.9	mΩ
		V_{GS} = 10 V; I_D = 5 A; T_j = 150 °C; see <u>Figure 13</u> ; see <u>Figure 12</u>	-	19.9	23.4	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 12	-	11.1	13	mΩ
R_G	internal gate resistance (AC)	f = 1 MHz	-	1.33	-	Ω
Dynamic ch	aracteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 5 \text{ A}$; $V_{DS} = 15 \text{ V}$; $V_{GS} = 10 \text{ V}$; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	11.7	-	nC
		$I_D = 5 \text{ A}$; $V_{DS} = 15 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	5.7	-	nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	10.5	-	nC
Q_{GS}	gate-source charge	$I_D = 5 \text{ A}; V_{DS} = 15 \text{ V}; V_{GS} = 10 \text{ V};$	-	1.5	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see <u>Figure 14</u> ; see <u>Figure 15</u>	-	1.1	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	0.4	-	nC
Q _{GD}	gate-drain charge		-	1.9	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 5 \text{ A}$; $V_{DS} = 15 \text{ V}$; see Figure 14; see Figure 15	-	2.52	-	V
C _{iss}	input capacitance	$V_{DS} = 15 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	744	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	143	-	pF
C _{rss}	reverse transfer capacitance		-	77	-	pF

 Table 6.
 Characteristics ...continued

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$t_{d(on)}$	turn-on delay time	$V_{DS} = 15 \text{ V}; R_L = 1 \Omega; V_{GS} = 4.5 \text{ V};$	-	5	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega; T_j = 25 \text{ °C}$	-	11	-	ns
t _{d(off)}	turn-off delay time		-	15	-	ns
t _f	fall time		-	5	-	ns
Source-dra	in diode					
V_{SD}	source-drain voltage	$I_S = 5 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see <u>Figure 17</u>	-	0.81	1.2	V
t _{rr}	reverse recovery time	$I_S = 5 \text{ A}; dI_S/dt = 100 \text{ A/}\mu\text{s};$	-	19	-	ns
Q_r	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 15 \text{ V}$	-	11	-	nC

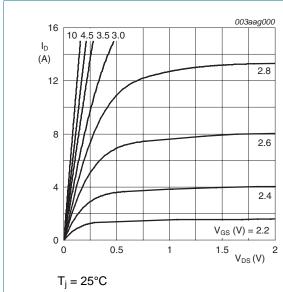


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

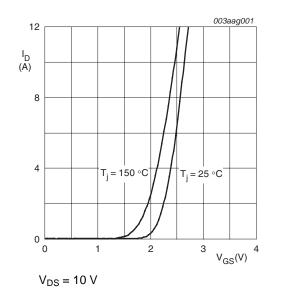


Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

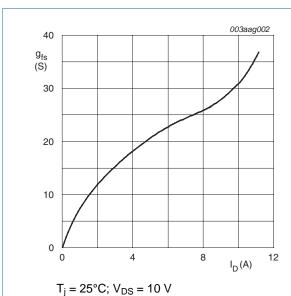


Fig 7. Forward transconductance as a function of drain current; typical values

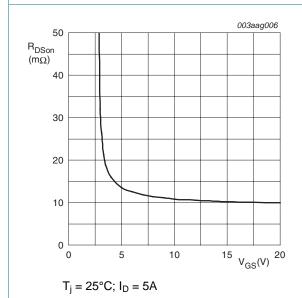


Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values

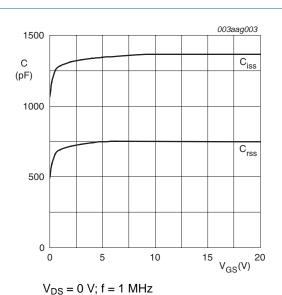
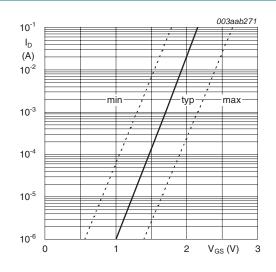


Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



 $T_j = 25\,^{\circ}C; V_{DS} = 5V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage

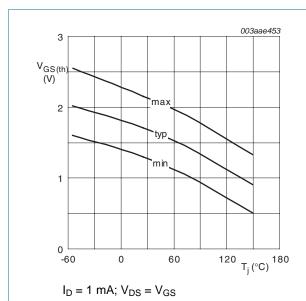


Fig 11. Gate-source threshold voltage as a function of junction temperature

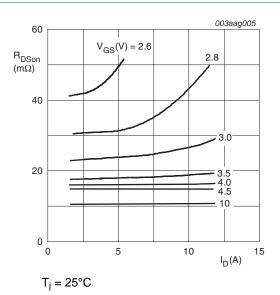


Fig 12. Drain-source on-state resistance as a function of drain current; typical values

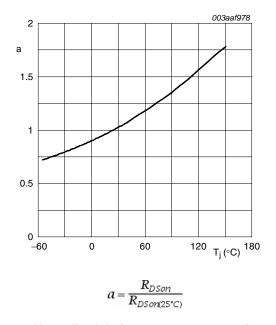


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

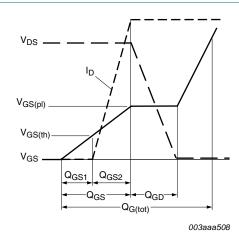


Fig 14. Gate charge waveform definitions

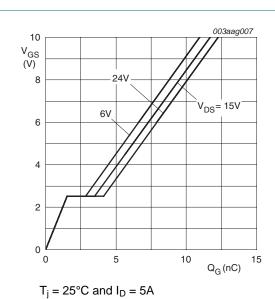
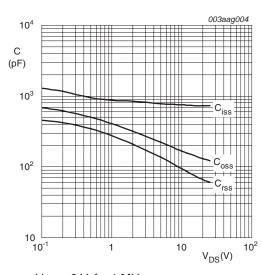
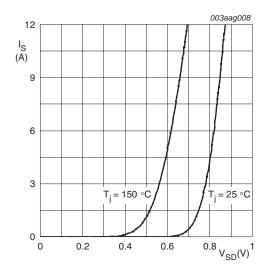


Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V, f = 1 MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



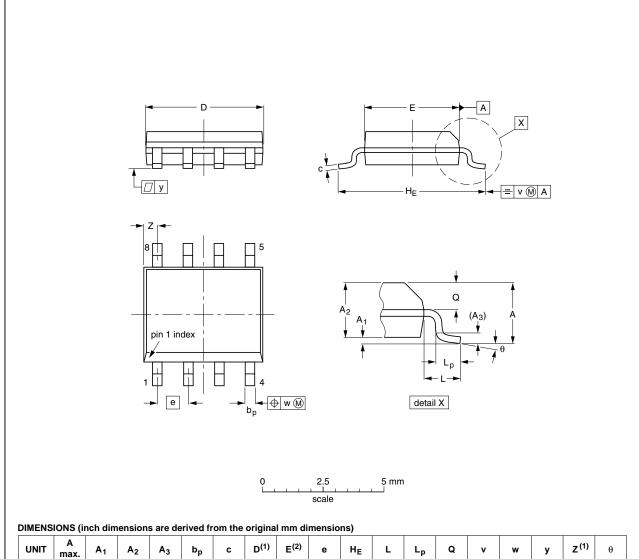
 $V_{GS} = 0 V$

Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

SO8: plastic small outline package; 8 leads; body width 3.9 mm

SOT96-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	e	HE	٦	Lp	σ	>	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	5.0 4.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.20 0.19	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.
- 2. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT96-1	076E03	MS-012			99-12-27 03-02-18	

Fig 18. Package outline SOT96-1 (SO8)

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Revision history

Table 7. **Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN013-30KL v.1	20110414	Objective data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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N-channel 30 V 13 m Ω logic-level MOSFET in SO8

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